<u>esemi</u>

Features

- This Device is Designed for Low Level Analog Switching Applications, Sample and Hold Circuits and Chopper Stabilized Amplifiers.
- Sourced from Process 51.
- This is a Pb–Free and a Halide Free Device



SOT-23

ABSOLUTE MAXIMUM RATINGS (Note 1), (Note 2)

(T_A = 25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{DG}	Drain-Gate Voltage	40	V
V _{GS}	Gate-Source Voltage	-40	V
I _{GF}	Forward Gate Current	50	mA
T _J , T _{STG} Operating and Storage Junction Temperature Range		–55 to + 150	°C

THERMAL CHARACTERISTICS (T_A = 25° C unless otherwise noted)

Symbol	Characteristic	Max	Unit
PD	Total Device Dissipation	350	mW
	Derate above 25°C	2.8	mW/°C
Reja	Thermal Resistance, Junction to Ambient (Note 3)	357	°C/W

Device mounted on FR–4 PCB 1.6" \times 1.6" \times 0.06".



ELECTRICAL CHARACTERISTICS (T_A = $25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Max	Unit
OFF CHARACTERISTICS					
V _{(BR)GSS}	Gate-Source Breakdown Voltage	$I_G = 1 \ \mu A, V_{DS} = 0$	-40	-	V
V _{GS} (off)	Gate-Source Cut-Off Voltage	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 1 \text{ nA}$	-1.0	-5.0	V
I _{DGO}	Drain-Gate Leakage Current	$ \begin{array}{l} V_{DG} = 20 \; V, \; I_S = 0 \\ V_{DG} = 20 \; V, \; I_S = 0, \; T_A = 150^\circ C \end{array} $	-	-200 -400	pA nA
I _D (off)	Drain Cutoff Leakage Current			200 400	pA nA
ON CHARACTE	RISTICS				
I _{DSS}	Zero-Gate Voltage Drain Current (Note 4)	$V_{DS} = 20 \text{ V}, \text{ I}_{GS} = 0$	8	-	mA
V _{DS} (on)	Drain-Source On Voltage	$I_D = 2.5 \text{ mA}, V_{GS} = 0$	-	0.2	V
r _{DS} (on)	Drain-Source On Resistance	I _D = 1 mA, V _{GS} = 0	-	80	Ω
SMALL SIGNAL	_ CHARACTERISTICS				
r _{DS} (on)	Drain-Source On Resistance	$V_{DS} = V_{GS} = 0$, f = 1 kHz	-	80	Ω
C _{iss}	Input Capacitance	V_{DS} = 20 V, V_{GS} = 0 V, f = 1.0 MHz	-	16	pF
C _{rss}	Reverse Transfer Capacitance	V _{DS} = -20 V, f = 1.0 MHz	-	5	pF
SWITCHING CHARACTERISTICS					
t _{On}	Turn-On Time	I _{D(on)} = 3.0 mA	-	60	ns
t _{Off}	Turn-Off Time	V _{GS(off)} = 3.0 V	-	80	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1%.

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NDTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL. З.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS		INCHES			
DIM	MIN.	NDM.	MAX.	MIN.	NDM.	MAX.
A	0.89	1.00	1.11	0.035	0.039	0.044
A1	0.01	0.06	0.10	0.000	0.002	0.004
b	0.37	0.44	0.50	0.015	0.017	0.020
с	0.08	0.14	0.20	0.003	0.006	0.008
D	2.80	2.90	3.04	0.110	0.114	0.120
E	1.20	1.30	1.40	0.047	0.051	0.055
e	1.78	1.90	2.04	0.070	0.075	0.080
L	0.30	0.43	0.55	0.012	0.017	0.022
L1	0.35	0.54	0.69	0.014	0.021	0.027
HE	2.10	2.40	2.64	0.083	0.094	0.104
Т	0*		10*	0*		10*



For additional information on our Pb-Free strategy and soldering details, please download the IN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D. *

Ver.1.0